

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination BEIER ET AL.	
		10/597,198	Examiner	Art Unit 3742
		SANG Y. PAIK	Page 1 of 1	

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,864,463	03-2005	Ikeda, Fumihide	219/390
*	B	US-6,225,607	05-2001	Has et al.	219/448.11
*	C	US-6,462,316	10-2002	Berkcan et al.	219/502
*	D	US-6,118,107	09-2000	Kobrich, Holger	219/502
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
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	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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